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U.S. UTILITY Patent Application

PATENT NUMBER and  
ISSUE DATE

APPL NUM 10082520	FILING DATE 02/22/2002	CLASS <del>438</del> 356	SUBCLASS <del>11.630</del> 2877	GAU <del>2012</del> 2877	EXAMINER Pham KESHAVAN
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35 4 503 2877

\*\*CONTINUING DATA VERIFIED: none

\*\* FOREIGN APPLICATIONS VERIFIED: yes  
JAPAN 2001-226984 07/27/2001

PG-PUB DO NOT PUBLISH ☐

RESCIND ☐

Foreign priority claimed ☒ yes ☐ no  
35 USC 119 conditions met ☒ yes ☐ no  
Verified and Acknowledged Examiners's initials HP

ATTORNEY DOCKET NO  
16869P-04160US

TITLE : Method and apparatus for measuring thickness of thin film and device manufacturing method  
using same

<b>NOTICE OF ALLOWANCE MAILED</b>		<b>CLAIMS ALLOWED</b>	
		Total Claims	Print Claim for O.G.
<b>ISSUE FEE</b>		<b>DRAWING</b>	
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg. Print Fig.
		Application Examiner	
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		<b>PREPARED FOR ISSUE</b>	
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